Applicant(s)/Patent Under Application/Control No. Reexamination 10/749,045 CHEN ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 Mathieu D. Vargot 1732 **U.S. PATENT DOCUMENTS Document Number** Date Classification Name Country Code-Number-Kind Code MM-YYYY * US-4,442,061 04-1984 264/328.7 Matsuda et al. В US-С US-US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R s T **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)

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